




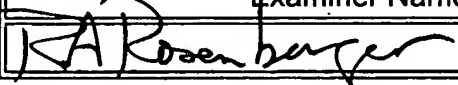




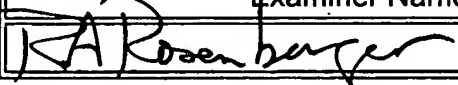




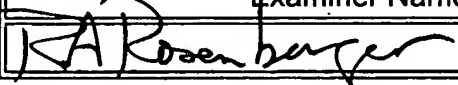


ELECTRONIC INFORMATION DISCLOSURE STATEMENT

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Title of Invention	SYSTEMS AND METHODS FOR MULTI-DIMENSIONAL METROLOGY AND/OR INSPECTION OF A SPECIMEN																																																										
<p>Application Number: 10/688503 </p> <p>Confirmation Number: 1964</p> <p>First Named Applicant: Tim Wihl</p> <p>Attorney Docket Number: 5589-04301</p> <p>Search string: (5999266 or 6181472 or 6268923 or 20020018118).pn.</p> <p>US Patent Documents</p> <p>Note: Applicant is not required to submit a paper copy of cited US Patent Documents</p> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Patent No.</th><th>Date</th><th>Patentee</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td></td><td>1</td><td>5999266</td><td>1999-12-07</td><td>Takahashi et al.</td><td></td><td></td><td></td></tr><tr><td></td><td>2</td><td>6181472</td><td>2001-01-30</td><td>Liu</td><td></td><td></td><td></td></tr><tr><td></td><td>3</td><td>6268923</td><td>2001-07-31</td><td>Michniewicz et al.</td><td></td><td></td><td></td></tr></tbody></table> <p>US Published Applications</p> <p>Note: Applicant is not required to submit a paper copy of cited US Published Applications</p> <table border="1"><thead><tr><th>init</th><th>Cite.No.</th><th>Pub. No.</th><th>Date</th><th>Applicant</th><th>Kind</th><th>Class</th><th>Subclass</th></tr></thead><tbody><tr><td></td><td>1</td><td>20020018118</td><td>2002-02-14</td><td>Coulombe et al.</td><td></td><td></td><td></td></tr></tbody></table> <p>Signature</p> <table border="1"><thead><tr><th>Examiner Name</th><th>Date</th></tr></thead><tbody><tr><td></td><td>2/28/2006</td></tr></tbody></table>								init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass		1	5999266	1999-12-07	Takahashi et al.					2	6181472	2001-01-30	Liu					3	6268923	2001-07-31	Michniewicz et al.				init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass		1	20020018118	2002-02-14	Coulombe et al.				Examiner Name	Date		2/28/2006
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Form PTO-1449 (modified 12/2006)
List of Patents and Publications
For Applicant's Information
Disclosure Statement
 (Use several sheets if necessary)

ATX. DKT. NO. 5589-04301

SERIAL NO. 10/688,503

APPLICANT: Wihl et al.

GROUP: Unknown

FILING DATE: October 17, 2003

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO
RWZ	A1	01/71279	2001-09-27	WO			
RWZ	A2	00/36525	2000-06-22	WO			

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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